<u>Claims</u>

- 1-32. (withdrawn)
- 33. (original) A sampler, comprising:
- a signal conductor;
- a sampling diode in electrical communication with the signal conductor; and
- a non-linear transmission line that includes a non-parallel waveguide and a plurality of varactors, the non-linear transmission line configured to deliver sampling strobe pulses to the sampling diode.
- 34. (original) The sample of claim 33, further comprising an intermediate frequency (IF) waveguide configured to electrically connect to the signal conductor as controlled by the sampling diode.
- 35. (original) The sampler of claim 34, further comprising a measurement system configured to receive portions of an electrical signal applied to the signal conductor from the IF waveguide.
- 36. (original) The sampler of claim 35, wherein the measurement system is configured to produce an equivalent-time representation of the electrical signal.

- 37. (original) The sampler of claim 34, further comprising a measurement system configured to receive portions of an electrical signal applied to IF waveguide from the signal conductor.
- 38. (original) The sampler of claim 37, wherein the measurement system is configured to produce an equivalent-time representation of the electrical signal.
- 39. (original) The sampler of claim 33, wherein the non-linear transmission line includes a plurality of Schottky mesa diodes.
- 40. (original) The sampler of claim 33, wherein the non-parallel waveguide includes at least one periodically repeated waveguide section.
- 41. (original) The sampler of claim 33, further comprising a strobe waveguide transition configured to receive the sampling strobe pulses from the non-linear transmission line and to deliver enhanced strobe pulses to the sampling diode.
 - 42. (original) The sampler of claim 33, wherein the non-parallel waveguide is a slotline.
- 43. (original) The sampler of claim 33, wherein the non-parallel waveguide is a coplanar stripline.

- 44. (currently amended) A sampling circuit, comprising:
- a first <u>nonparallel</u> waveguide configured to receive a sampling strobe and having a first impedance;

a second <u>nonparallel</u> waveguide configured to receive the sampling strobe from the first <u>nonparallel</u> waveguide and having a second impedance, wherein the first impedance and the second impedance are configured to produce an enhanced sampling strobe; and

at least one diode electrically controlled by the sampling strobe and configured to deliver a sampled portion of an input signal to an output conductor.

- 45. (currently amended) The sampling circuit of claim 44, wherein the second nonparallel waveguide includes a termination configured to direct an inverted portion of the enhanced sampling strobe to the sampling diode, thereby establishing a sampling window.
- 46. (currently amended) The sampling circuit of claim 45, wherein the first <u>nonparallel</u> waveguide and the second nonparallel waveguide are slotlines.
- 47. (original) The sampling circuit of claim 45, further comprising an IF waveguide configured to deliver the sampled portion to the output conductor.
 - 48-52. (withdrawn)
 - 53. (new) A sampler, comprising:

a signal conductor;

a sampling diode in electrical communication with the signal conductor; and a non-linear transmission line that includes a non-parallel waveguide and a plurality of varactors, the non-linear transmission line configured to deliver sampling strobe pulses to the sampling diode, wherein the non-parallel waveguide includes at least one periodically repeated waveguide section.

- 54. (new) The sampler of claim 53, further comprising an intermediate frequency (IF) waveguide configured to electrically connect to the signal conductor as controlled by the sampling diode.
- 55. (new) The sampler of claim 54, further comprising a measurement system configured to receive portions of an electrical signal applied to the signal conductor from the IF waveguide.
- 56. (new) The sampler of claim 55, wherein the measurement system is configured to produce an equivalent-time representation of the electrical signal.
- 57. (new) The sampler of claim 54, further comprising a measurement system configured to receive portions of an electrical signal applied to IF waveguide from the signal conductor.

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- 58. (new) The sampler of claim 57, wherein the measurement system is configured to produce an equivalent-time representation of the electrical signal.
- 59. (new) The sampler of claim 53, wherein the non-linear transmission line includes a plurality of Schottky mesa diodes.
- 60. (new) The sampler of claim 53, further comprising a strobe waveguide transition configured to receive the sampling strobe pulses from the non-linear transmission line and to deliver enhanced strobe pulses to the sampling diode.
 - 61. (new) The sampler of claim 63, wherein the non-parallel waveguide is a slotline.
- 62. (new) The sampler of claim 53, wherein the non-parallel waveguide is a coplanar stripline.
 - 63. (new) A sampler, comprising:
 - a signal conductor;
 - a sampling diode in electrical communication with the signal conductor; and
- a non-linear transmission line that includes first, second, and third non-parallel waveguide sections having first, second, and third characteristic impedances, respectively, and a plurality of varactors, the non-linear transmission line configured to deliver sampling strobe pulses to the sampling diode.

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- 64. (new) The sample of claim 63, further comprising an intermediate frequency (IF) waveguide configured to electrically connect to the signal conductor as controlled by the sampling diode.
- 65. (new) The sampler of claim 64, further comprising a measurement system configured to receive portions of an electrical signal applied to the signal conductor from the IF waveguide.
- 66. (new) The sampler of claim 65, wherein the measurement system is configured to produce an equivalent-time representation of the electrical signal.
- 67. (new) The sampler of claim 64, further comprising a measurement system configured to receive portions of an electrical signal applied to IF waveguide from the signal conductor.
- 68. (new) The sampler of claim 67, wherein the measurement system is configured to produce an equivalent-time representation of the electrical signal.
- 69. (new) The sampler of claim 63, wherein the non-linear transmission line includes a plurality of Schottky mesa diodes.

- 70. (new) The sampler of claim 63, wherein at least one of the non-parallel waveguide sections is periodically repeated.
- 71. (new) The sampler of claim 63, further comprising a strobe waveguide transition configured to receive the sampling strobe pulses from the non-linear transmission line and to deliver enhanced strobe pulses to the sampling diode.
 - 72. (new) The sampler of claim 63, wherein the non-parallel waveguide is a slotline.
- 73. (new) The sampler of claim 63, wherein the non-parallel waveguide is a coplanar stripline.

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